

TIME-OF-FLIGHT SECONDARY ION MASS SPECTROMETER (TOF-SIMS)

Tuesday, May 17, 10-11 AM MST

Speaker: Michael Walker

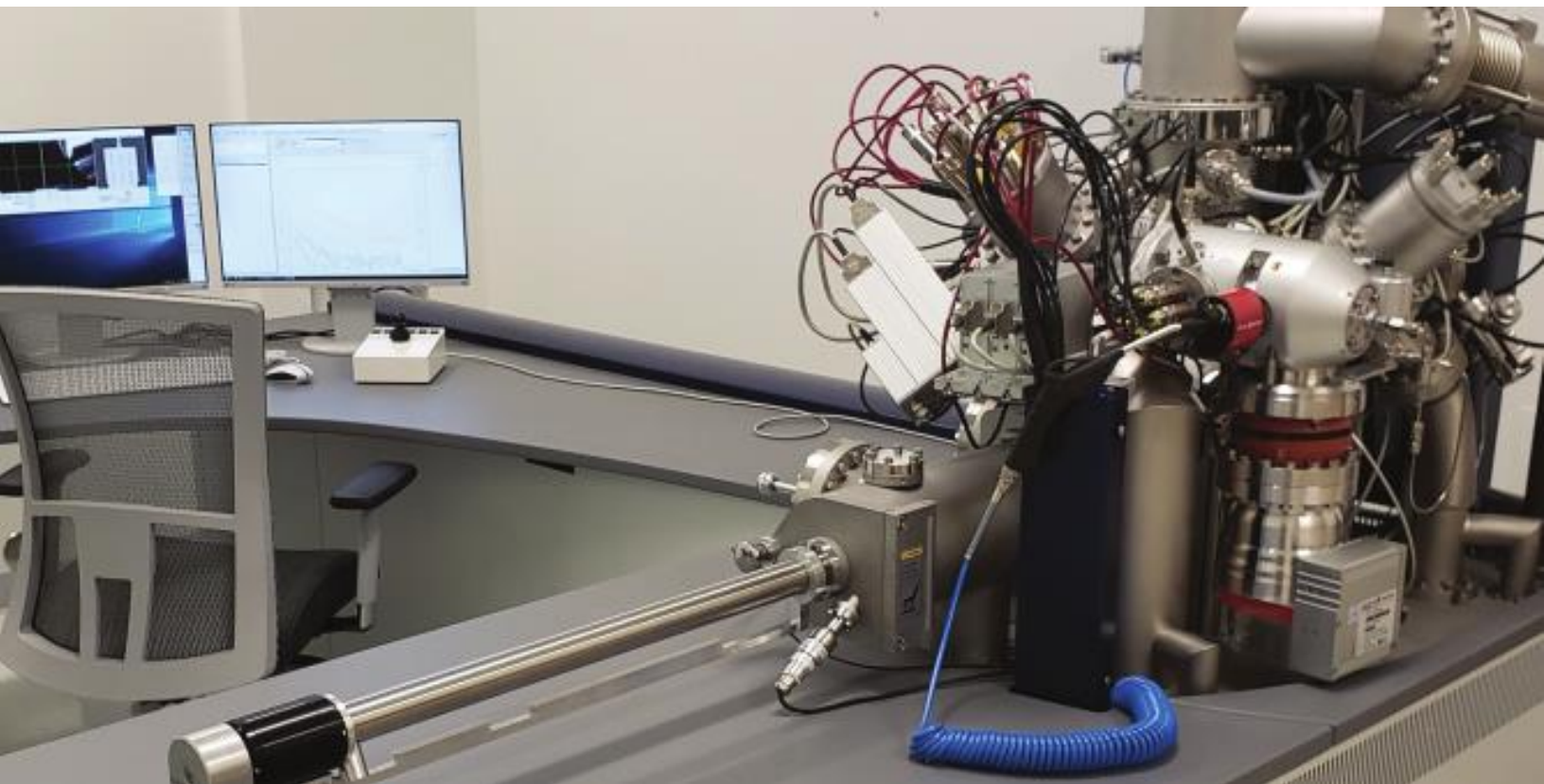
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[Michael Walker](#)'s background spans nearly 20 years of experience in the Semiconductor industry. Having worked for Motorola, Texas Instruments, and Samsung Austin Semiconductor, Michael's gained experience in Diffusion, Failure Analysis, Yield Enhancement, and Research and Development. At Samsung, Michael expanded his expertise in the Surface Analysis group utilizing TOF-SIMS, MS-SIMS, XPS, AES, and AFM to support the manufacturing of integrated circuits.

Michael joined Dr. Corinne Packard's [research group](#) in 2018 as a TOF-SIMS specialist tasked with running and maintaining Mines' state-of-the-art ION-TOF V TOF-SIMS instrument to assist students, faculty, and industry with their research projects. During his time here at Mines, while utilizing the TOF-SIMS, Michael has contributed to the study in such fields as photovoltaics (Si, CIGS, CdTe, and CdTeSe), steels, medical instruments, medical implants, ceramics, fuel cells, semiconductors, cell tower electronics, spin transport devices, quantum information science (quantum computing), automotive, nuclear energy, body armor, solid-state electrochemistry, additive manufacturing, low-temperature electrochemical devices, and optoelectronics.